

PAL10/10016C4-2 (PLCC Only) 2 ns ECL ASPECT™ Programmable Array Logic

General Description

The PAL10/10016C4-2 is a member of the National Semiconductor 28-pin high speed ECL PAL® family. This device utilizes National Semiconductor's ASPECT (Advanced Single Poly ECL Technology) Process with a newly developed tungsten fuse technology to provide the highest-speed user-programmable replacements for conventional ECL SSI-MSI logic with significant chip-count reduction. The JEDEC fuse-map format and programming algorithm of this device is compatible with those of all prior ECL PAL products from National.

Programmable logic devices provide convenient solutions for a wide variety of application-specific functions, including random logic, custom decoders, state machines, etc. By programming fuse links to configure AND/OR gate connections, the system designer can implement custom logic as convenient sum-of-products Boolean functions. System prototyping and design iterations can be performed quickly using these off-the-shelf products.

The PAL10/10016C4-2 logic array has a total of 16 complementary input pairs, 32 product terms and 4 complementary output functions. Each output function is the OR-sum of 8 product terms. Each product term is satisfied when all array inputs which are connected to it (via intact fuses) are in the correct state. Complementary outputs eliminate the need

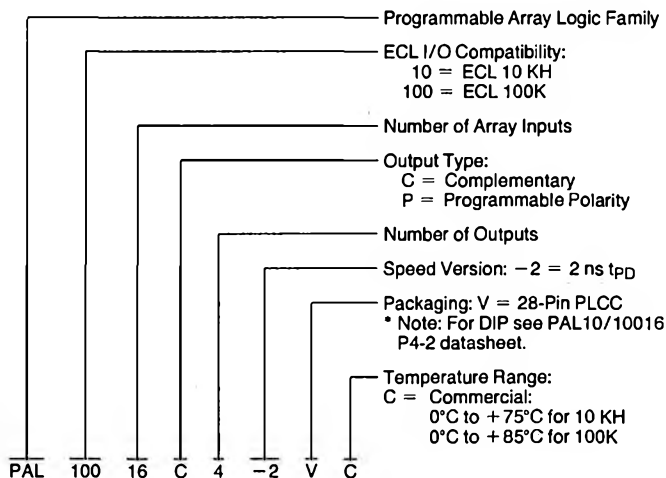
for external inverters and allow for more convenient output OR-tying. They are also suitable for differential sensing for increased noise immunity. All input pins have on-chip 50 kΩ pull-down resistors.

Programming equipment and software make PAL design development quick and easy. Programming is accomplished using TTL voltage levels and is therefore supported by several conventional TTL PLD programming units. After programming and verifying the logic array, an additional security fuse may be programmed to prevent direct copying of proprietary logic designs.

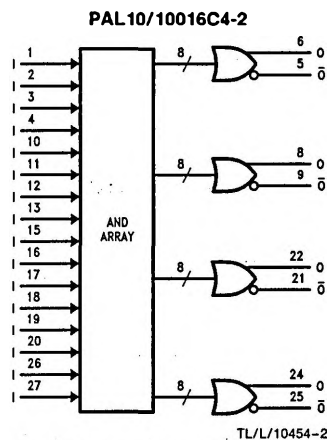
Features

- Highest speed: $t_{PD} = 2$ ns max
- Full 28-pin function
- Programmable replacement for ECL logic
- Both 100K and 10 KH I/O compatible versions
- Four output functions with complementary outputs
- Improved programmability tungsten fuses
- Security fuse to prevent direct copying
- Programmed on conventional TTL PLD programmers
- Fully Supported by PLAN™ Software
- High density-High performance 28-pin PLCC package

Ordering Information



Block Diagram



$V_{EE} = -14$, $V_{CC} = 28$, V_{CC0} (5, 6, 8, 9) = 7
 V_{CC0} (21, 22, 24, 25) = 23
 Pinout applies to 28-pin PLCC

Absolute Maximum Ratings

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Temperature Under Bias	-55°C to +125°C
Storage Temperature Range	-65°C to +150°C
V _{EE} Relative to V _{CC}	-7V to +0.5V
Input Voltage	V _{EE} to +0.5V

Output Current	-50 mA
Lead Temperature (Soldering, 10 seconds)	300°C
ESD Tolerance	TBD
C _{ZAP}	= 100 pF
R _{ZAP}	= 1500Ω
Test Method:	Human Body Model
Test Specification:	NSC SOP-5-028

Recommended Operating Conditions

Symbol	Parameter	Min	Typ	Max	Units	
V _{EE}	Supply Voltage	10 KH	-5.46	-5.2	-4.94	V
		100K	-4.80	-4.5	-4.20	
T	Operating Temperature (Note)	10 KH	0		+75	°C
		100K	0		+85	

Electrical Characteristics Over Recommended Operating Conditions

Output Load = 50Ω to -2.0V

Symbol	Parameter	Conditions	T _A	Min	Max	Units	
V _{IH}	High Level Input Voltage	Guaranteed Input Voltage High For All Inputs	10 KH	0°C	-1170	-840	mV
				+25°C	-1130	-810	
				+75°C	-1070	-735	
V _{IL}	Low Level Input Voltage	Guaranteed Input Voltage Low For All Inputs	10 KH	0°C to +85°C	-1165	-880	mV
V _{OH}	High Level Output Voltage	V _{IN} = V _{IH} Max. or V _{IL} Min.	10 KH	0°C	-1950	-1480	mV
				+25°C	-1950	-1480	
				+75°C	-1950	-1450	
V _{OL}	Low Level Output Voltage	V _{IN} = V _{IH} Max. or V _{IL} Min.	10 KH	0°C to +85°C	-1810	-1475	mV
I _{IH}	High Level Input Current	V _{IN} = V _{IH} Max.	10 KH	0°C to +75°C		220	μA
I _{IL}	Low Level Input Current	V _{IN} = V _{IL} Min.	10 KH	0°C to +75°C	0.5		μA
I _{EE}	Supply Current	V _{EE} = Min. All Inputs and Outputs Open	10 KH	0°C to +75°C	-220		mA
			100K	0°C to +85°C			

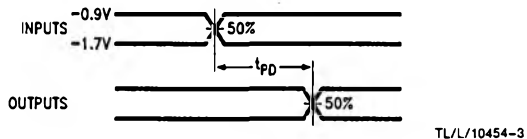
Note: Operating temperatures for circuits in PLCC packages are specified as ambient temperatures (T_A) with circuits in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained.

Switching Characteristics

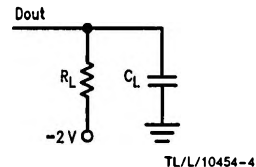
Over Recommended Operating Conditions, Output load: $R_L = 50\Omega$ to $-2.0V$, $C_L = 5\text{ pF}$ to GND

Symbol	Parameter	Measured Test Conditions	Min	Max	Units
t_{PD}	Input to Output	Measured at 50% points		2.0	ns
t_r	Output Rise Time	Measured between 20% and 80% points	0.25	1.25	ns
t_f	Output Fall Time		0.25	1.25	ns

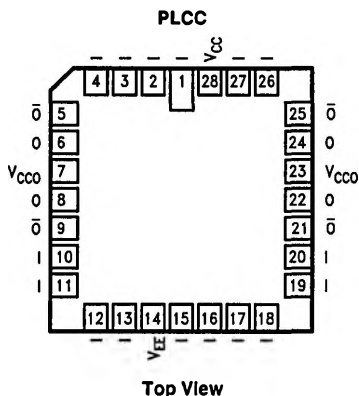
Timing Measurements



Test Load



Connection Diagram



Order Number PAL1016C4-2/PAL10016C4-2
See NS Package Number V28A

Functional Testing

As with all field-programmable devices, the user of the ECL PAL devices provides the final manufacturing step. While National's PAL devices undergo extensive testing when they are manufactured, their logic function can be fully tested only after they have been programmed to the user's pattern.

To ensure that the programmed PAL devices will operate properly in your system, National Semiconductor (along with most other manufacturers of PAL devices) strongly recommends that devices be functionally tested before being installed in your system. Even though the number of post-programming functional failures is small, testing the logic function of the PAL devices before they reach system assembly will save board debugging and rework costs. For more information about the functional testing of PAL devices, please refer to National Semiconductor's Application Note #351 and the *Programmable Logic Design Guide*.

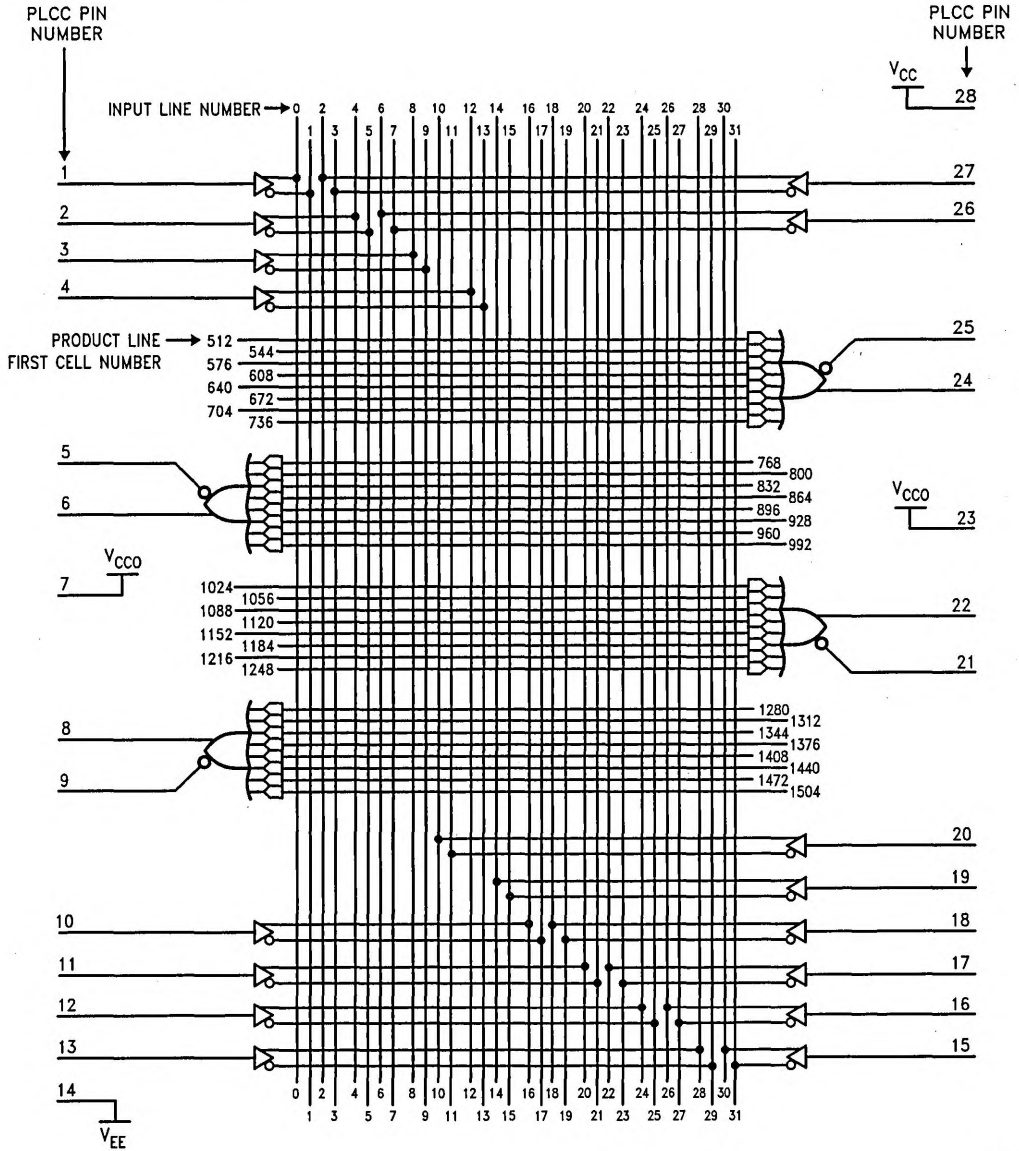
Design Development Support

A variety of software tools and programming hardware is available to support the development of designs using PAL

products. Typical software packages accept Boolean logic equations to define desired functions. Most are available to run on personal computers and generate JEDEC-compatible "fuse maps". The industry-standard JEDEC format ensures that the resulting fuse-map files can be downloaded into a large variety of programming equipment. Many software packages and programming units support a large variety of programmable logic products as well. The PLAN software package from National Semiconductor supports all programmable logic products available from National and is fully JEDEC-compatible. PLAN software also provides automatic device selection based on the designer's Boolean logic equations.

A detailed logic diagram showing all JEDEC fuse-map addresses for the PAL10/10016C4-2 is provided for direct map editing and diagnostic purposes. For a list of current software and programming support tools available for these devices, please contact your local National Semiconductor sales representative or distributor. If detailed specifications of the ECL PAL programming algorithm are needed, please contact the National Semiconductor Programmable Device Support Department.

Logic Diagram—PAL1016C4-2/PAL10016C4-2



JEDEC logic array cell number = product line first cell number + input line number

TL/L/10454-6